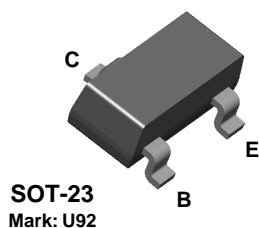


# BSR17A



## NPN General Purpose Amplifier

This device is designed as a general purpose amplifier and switch. The useful dynamic range extends to 100 mA as a switch and to 100 MHz as an amplifier. Sourced from Process 23.

### Absolute Maximum Ratings\*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V <sub>CEO</sub>	Collector-Emitter Voltage	40	V
V <sub>CBO</sub>	Collector-Base Voltage	60	V
V <sub>EBO</sub>	Emitter-Base Voltage	6.0	V
I <sub>C</sub>	Collector Current - Continuous	200	mA
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range	-55 to +150	°C

\* These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

#### NOTES:

- 1) These ratings are based on a maximum junction temperature of 150 degrees C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

### Thermal Characteristics

TA = 25°C unless otherwise noted

Symbol	Characteristic	Max	Units
		*BSR17A	
P <sub>D</sub>	Total Device Dissipation Derate above 25°C	350 2.8	mW mW/°C
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient	357	°C/W

\* Device mounted on FR-4 PCB 40 mm X 40 mm X 1.5 mm.

## NPN General Purpose Amplifier

(continued)

## Electrical Characteristics

TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
<b>OFF CHARACTERISTICS</b>					
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage	$I_C = 10\ \mu A, I_B = 0$	60		V
$V_{(BR)CBO}$	Collector-Base Breakdown Voltage	$I_C = 1.0\ mA, I_E = 0$	40		V
$V_{(BR)EBO}$	Emitter-Base Breakdown Voltage	$I_E = 10\ \mu A, I_C = 0$	6.0		V
$I_{CBO}$	Collector-Cutoff Current	$V_{CB} = 30\ V, T_A = 150^\circ C$		5.0	$\mu A$
$I_{CEX}$	Collector-Cutoff Current	$V_{CE} = 30\ V, V_{EB} = 3.0\ V$		50	nA
$I_{BEX}$	Reverse Base Current	$V_{CE} = 30\ V, V_{EB} = 3.0\ V$		50	nA

## ON CHARACTERISTICS

$h_{FE}$	DC Current Gain	$I_C = 0.1\ mA, V_{CE} = 1.0\ V$ $I_C = 1.0\ mA, V_{CE} = 1.0\ V$ $I_C = 10\ mA, V_{CE} = 1.0\ V$ $I_C = 50\ mA, V_{CE} = 1.0\ V$ $I_C = 100\ mA, V_{CE} = 1.0\ V$	40 70 100 60 30	300	
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage*	$I_C = 10\ mA, I_B = 1.0\ mA$ $I_C = 50\ mA, I_B = 5.0\ mA$		0.2 0.3	V V
$V_{BE(sat)}$	Base-Emitter Saturation Voltage*	$I_C = 10\ mA, I_B = 1.0\ mA$ $I_C = 50\ mA, I_B = 5.0\ mA$	0.65	0.85 0.95	V V

## SMALL SIGNAL CHARACTERISTICS

$f_T$	Transition Frequency	$I_C = 20\ mA, V_{CE} = 20\ V,$ $f = 100\ MHz$	300		MHz
$C_{cb}$	Collector-Base Capacitance	$V_{CB} = 5.0\ V, I_E = 0, f = 1.0\ MHz$		4.0	pF
$C_{eb}$	Emitter-Base Capacitance	$V_{EB} = 0.5\ V, I_C = 0, f = 1.0\ MHz$		8.0	pF
$h_{ie}$	Input Impedance	$V_{CE} = 10\ V, I_C = 1.0\ mA, f = 1.0\ kHz$	1.0	10	k $\Omega$
$h_{fe}$	Small-Signal Current Gain	$V_{CE} = 10\ V, I_C = 1.0\ mA, f = 1.0\ kHz$	100	400	
$h_{oe}$	Output Admittance	$V_{CE} = 10\ V, I_C = 1.0\ mA, f = 1.0\ kHz$	1.0	40	$\mu S$

## SWITCHING CHARACTERISTICS

$t_d$	Delay Time	$I_C = 10\ mA, I_{B1} = 1.0\ mA,$ $V_{EB} = 0.5\ V$		35	ns
$t_r$	Rise Time			35	ns
$t_s$	Storage Time	$I_C = 10\ mA, I_{BON} = I_{BOFF} = 1.0\ mA$		200	ns
$t_f$	Fall Time			50	ns

\* Pulse Test: Pulse Width  $\leq 300\ \mu s$ , Duty Cycle  $\leq 2.0\ %$ 

## Spice Model

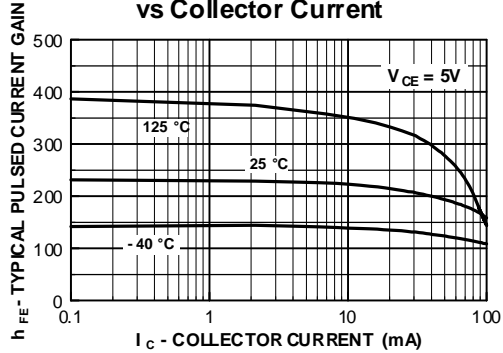
NPN (Is=6.734f Xti=3 Eg=1.11 Vaf=74.03 Bf=416.4 Ne=1.259 Ise=6.734 Ikf=66.78m Xtb=1.5 Br=.7371 Nc=2 Isc=0 Ikr=0 Rc=1 Cjc=3.638p Mjc=.3085 Vjc=.75 Fc=.5 Cje=4.493p Mje=.2593 Vje=.75 Tr=239.5n Tf=301.2p Itf=.4 Vtf=4 Xtf=2 Rb=10)

# NPN General Purpose Amplifier (continued)

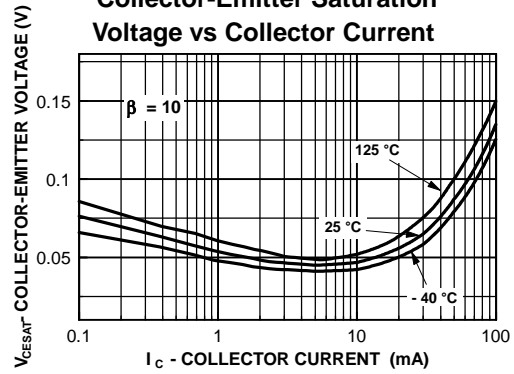
BSR17A

## Typical Characteristics

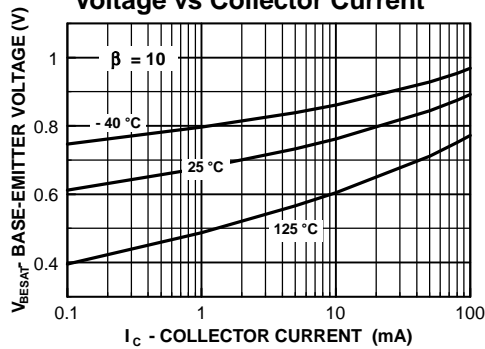
Typical Pulsed Current Gain  
vs Collector Current



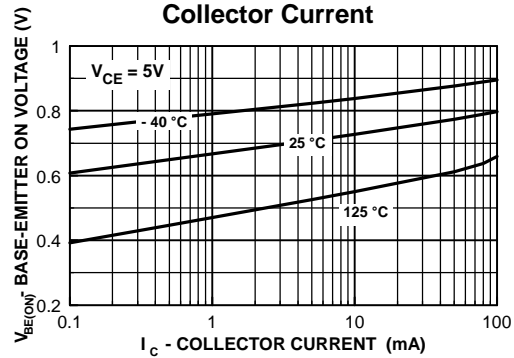
Collector-Emitter Saturation  
Voltage vs Collector Current



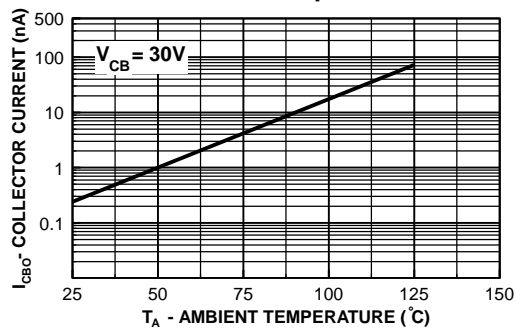
Base-Emitter Saturation  
Voltage vs Collector Current



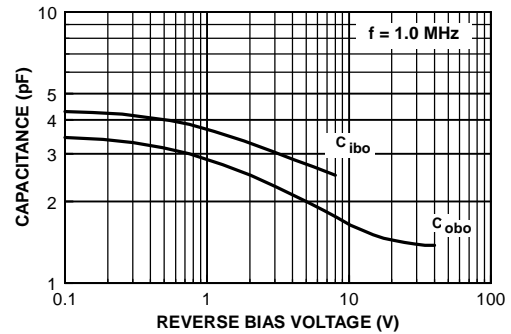
Base-Emitter ON Voltage vs  
Collector Current



Collector-Cutoff Current  
vs Ambient Temperature



Capacitance vs  
Reverse Bias Voltage

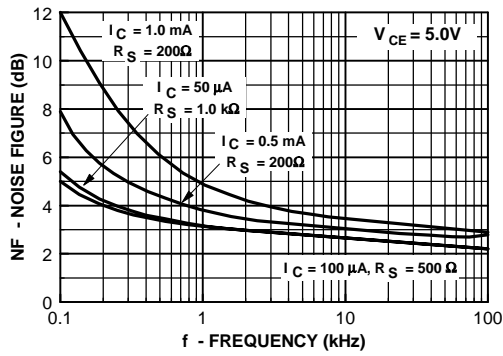


# NPN General Purpose Amplifier

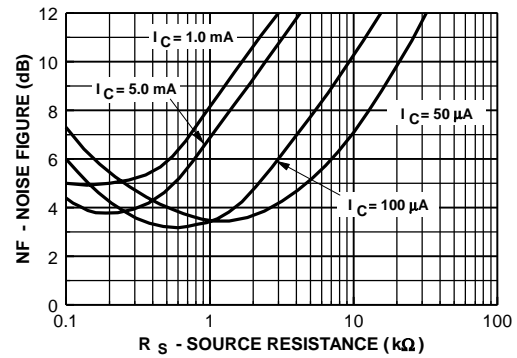
(continued)

## Typical Characteristics (continued)

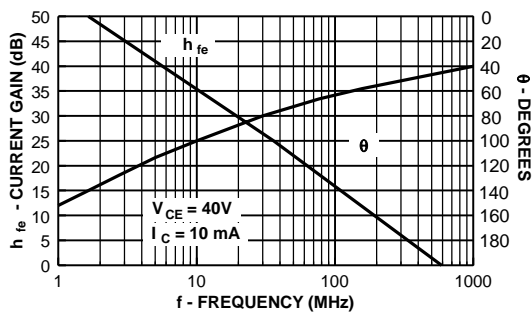
### Noise Figure vs Frequency



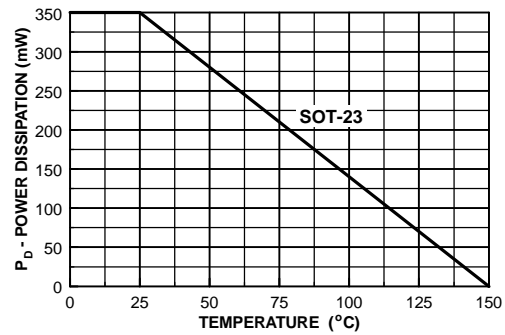
### Noise Figure vs Source Resistance



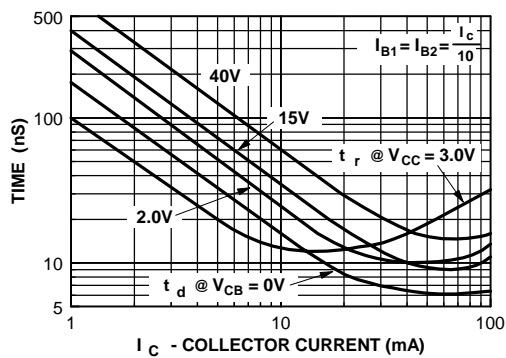
### Current Gain and Phase Angle vs Frequency



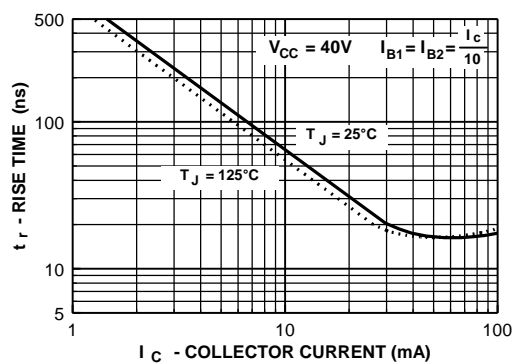
### Power Dissipation vs Ambient Temperature



### Turn-On Time vs Collector Current

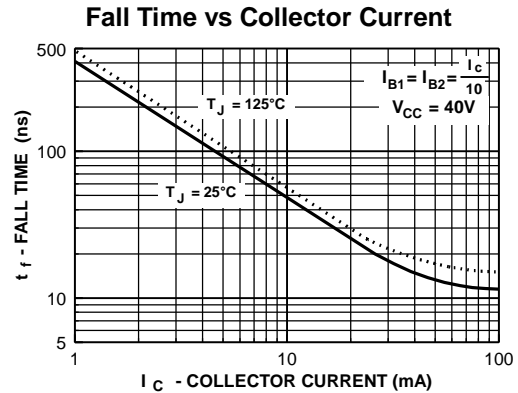
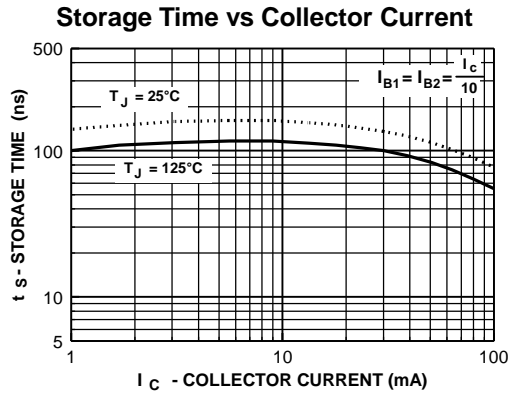


### Rise Time vs Collector Current



# NPN General Purpose Amplifier (continued)

## Typical Characteristics (continued)



## Test Circuits

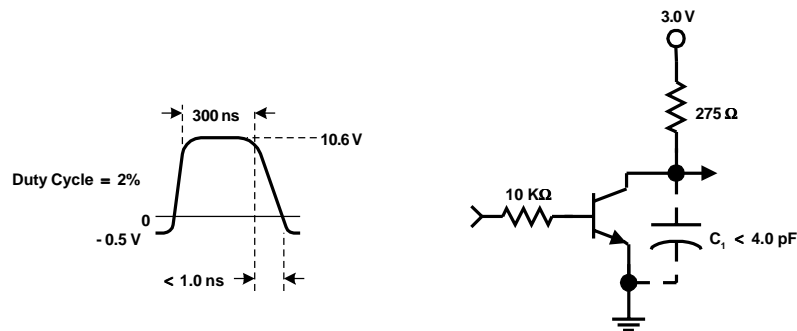


FIGURE 1: Delay and Rise Time Equivalent Test Circuit

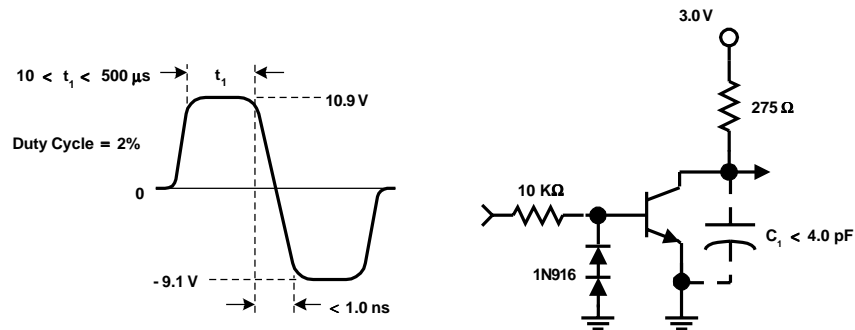


FIGURE 2: Storage and Fall Time Equivalent Test Circuit

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CROSSVOLT™	HiSeC™	QT Optoelectronics™	VCX™
DOME™	ISOPLANAR™	Quiet Series™	
E <sup>2</sup> CMOS™	MICROWIRE™	SILENT SWITCHER®	
EnSigna™	OPTOLOGIC™	SMART START™	
FACT™	OPTOPLANAR™	SuperSOT™-3	
FACT Quiet Series™	PACMAN™	SuperSOT™-6	
FAST®	POP™	SuperSOT™-8	

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